Search Notes					

Application/Control No.	Applicant(s)/Patent under Reexamination
10/708,826	BEENAU ET AL.
Examiner	Art Unit
Nam V. Nguyen	2635

SEARCHED				
Class	Subclass	Date	Examiner	
340	5.53	11/18/2005	NN	
340	5.2	11/18/2005	NN	
340	5.4+	11/18/2005	NN	
340	5.52	11/18/2005	NN	
340	5.6	11/18/2005	NN	
340	5.8+	11/18/2005	NN	
340	10.1	11/18/2005	NN	
340	10.4-10.5	11/18/2005	NN	
235	379	11/18/2005	NN	
235	380	11/18/2005	NN	
235	492	11/18/2005	NN	
705	35,54,76	11/18/2005	NN	
713	186	11/18/2005	NN	
713	194	11/18/2005	NN	

INTERFERENCE SEARCHED				
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SEARCH NOT (INCLUDING SEARCH S		
	DATE	EXMR
Search East: USPAT; US-PUB; EPO; JPO AND DERWENT	11/18/2005	NN